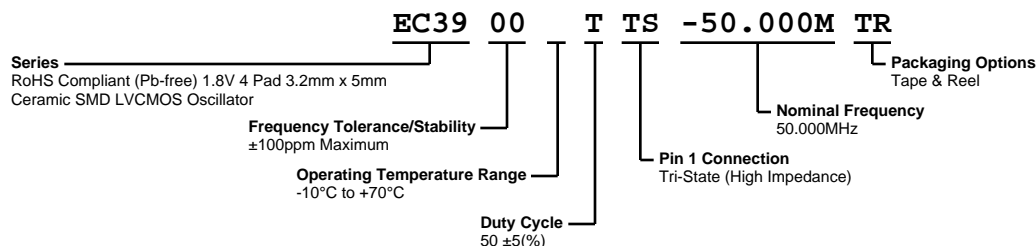


# EC3900TTS-50.000M TR



**ECLIPTEK**  
CORPORATION



## ELECTRICAL SPECIFICATIONS

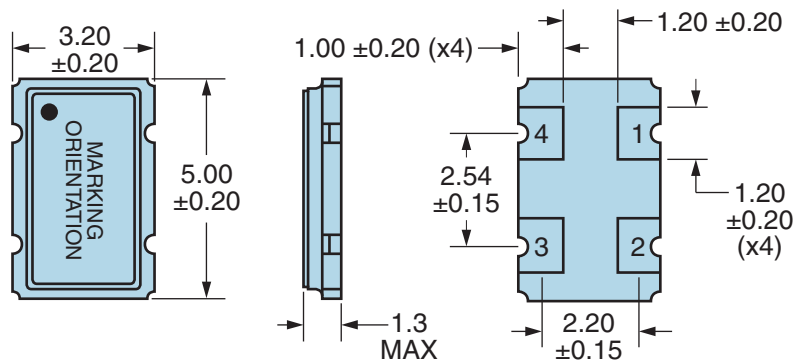
Nominal Frequency	50.000MHz
Frequency Tolerance/Stability	$\pm 100$ ppm Maximum (Inclusive of all conditions: Calibration Tolerance at $25^{\circ}\text{C}$ , Frequency Stability over the Operating Temperature Range, Supply Voltage Change, Output Load Change, First Year Aging at $25^{\circ}\text{C}$ , Shock, and Vibration)
Operating Temperature Range	$-10^{\circ}\text{C}$ to $+70^{\circ}\text{C}$
Supply Voltage	1.8Vdc $\pm 5\%$
Input Current	9mA Maximum
Output Voltage Logic High (Voh)	90% of Vdd Minimum ((IOH = -4mA))
Output Voltage Logic Low (Vol)	10% of Vdd Maximum ((IOH = +4mA))
Rise/Fall Time	4nSec Maximum (Measured at 20% to 80% of waveform)
Duty Cycle	50 $\pm 5$ (%) (Measured at 50% of waveform)
Load Drive Capability	15pF Maximum
Output Logic Type	CMOS
Pin 1 Connection	Tri-State (High Impedance)
Tri-State Input Voltage (Vih and Vil)	90% of Vdd Minimum or No Connect to Enable Output, 10% of Vdd Maximum to Disable Output (High Impedance)
Standby Current	10 $\mu$ A Maximum (Disabled Output: High Impedance)
RMS Phase Jitter	1pSec Maximum (12kHz to 20MHz offset frequency)
Start Up Time	10mSec Maximum
Storage Temperature Range	$-55^{\circ}\text{C}$ to $+125^{\circ}\text{C}$

## ENVIRONMENTAL & MECHANICAL SPECIFICATIONS

ESD Susceptibility	MIL-STD-883, Method 3015, Class 1, HBM: 1500V
Fine Leak Test	MIL-STD-883, Method 1014, Condition A
Flammability	UL94-V0
Gross Leak Test	MIL-STD-883, Method 1014, Condition C
Mechanical Shock	MIL-STD-883, Method 2002, Condition B
Moisture Resistance	MIL-STD-883, Method 1004
Moisture Sensitivity	J-STD-020, MSL 1
Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K
Resistance to Solvents	MIL-STD-202, Method 215
Solderability	MIL-STD-883, Method 2003
Temperature Cycling	MIL-STD-883, Method 1010, Condition B
Vibration	MIL-STD-883, Method 2007, Condition A



## MECHANICAL DIMENSIONS (all dimensions in millimeters)



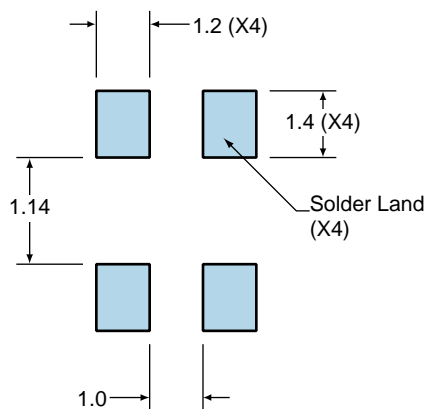
Note: Pin 1 Chamfer not shown.

PIN	CONNECTION
1	Tri-State
2	Ground
3	Output
4	Supply Voltage

LINE	MARKING
1	<b>E50.000</b> <i>E=Ecliptek Designator</i>
2	<b>XXYZZ</b> <i>XX=Ecliptek Manufacturing Code</i> <i>Y=Last Digit of the Year</i> <i>ZZ=Week of the Year</i>

## Suggested Solder Pad Layout

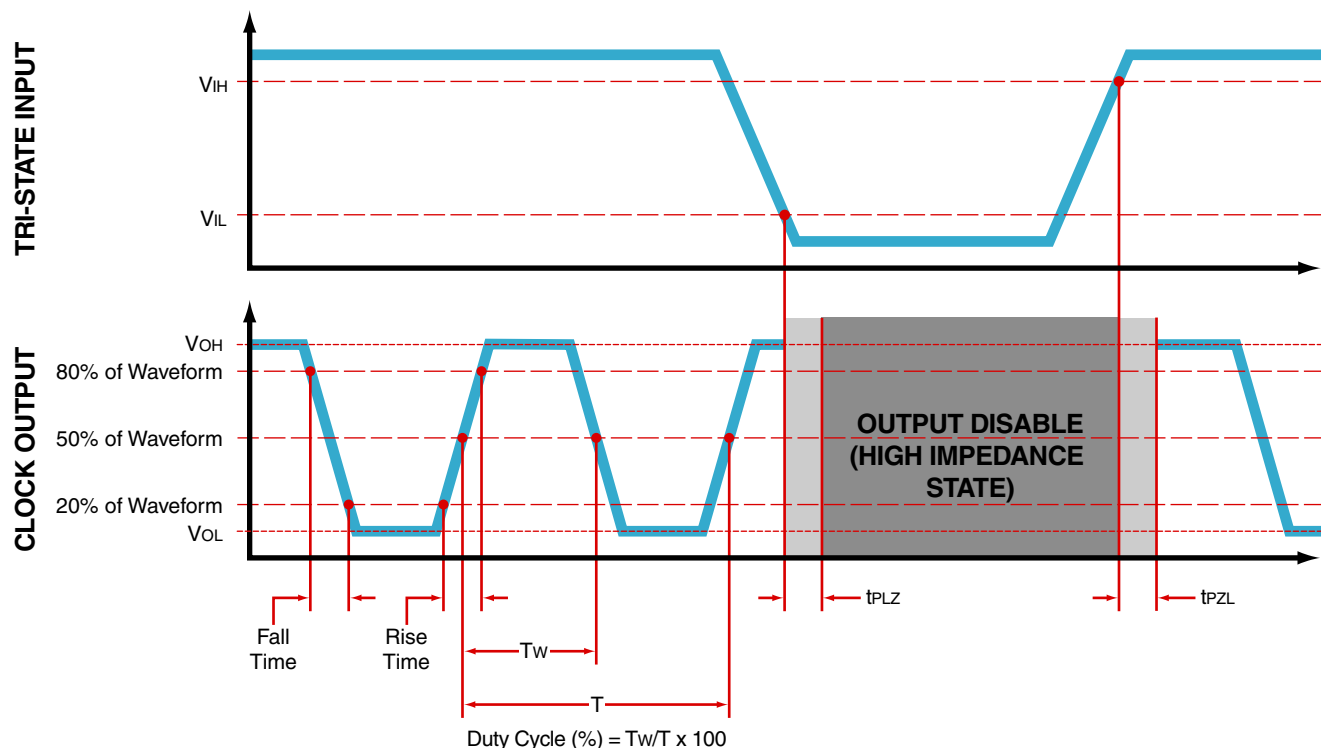
All Dimensions in Millimeters



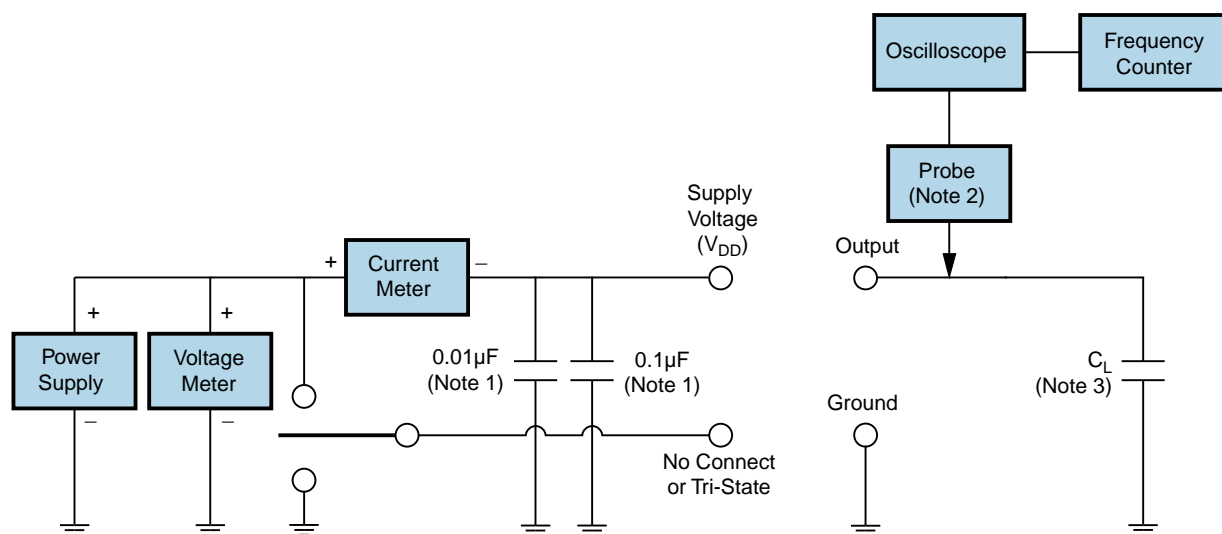
All Tolerances are  $\pm 0.1$

# EC3900TTS-50.000M TR

## OUTPUT WAVEFORM & TIMING DIAGRAM



## Test Circuit for CMOS Output



Note 1: An external 0.1  $\mu F$  low frequency tantalum bypass capacitor in parallel with a 0.01  $\mu F$  high frequency ceramic bypass capacitor close to the package ground and  $V_{DD}$  pin is required.

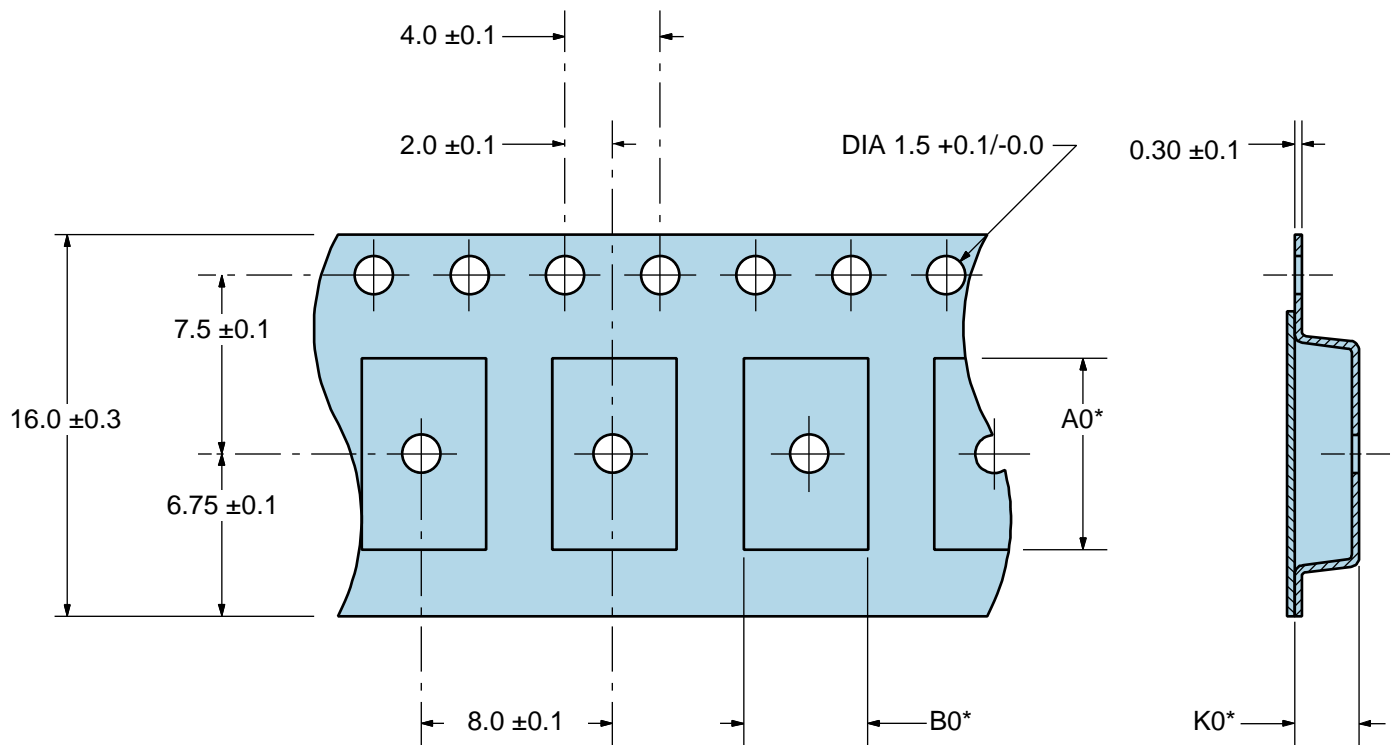
Note 2: A low capacitance (<12pF), 10X attenuation factor, high impedance (>10Mohms), and high bandwidth (>300MHz) passive probe is recommended.

Note 3: Capacitance value  $C_L$  includes sum of all probe and fixture capacitance.

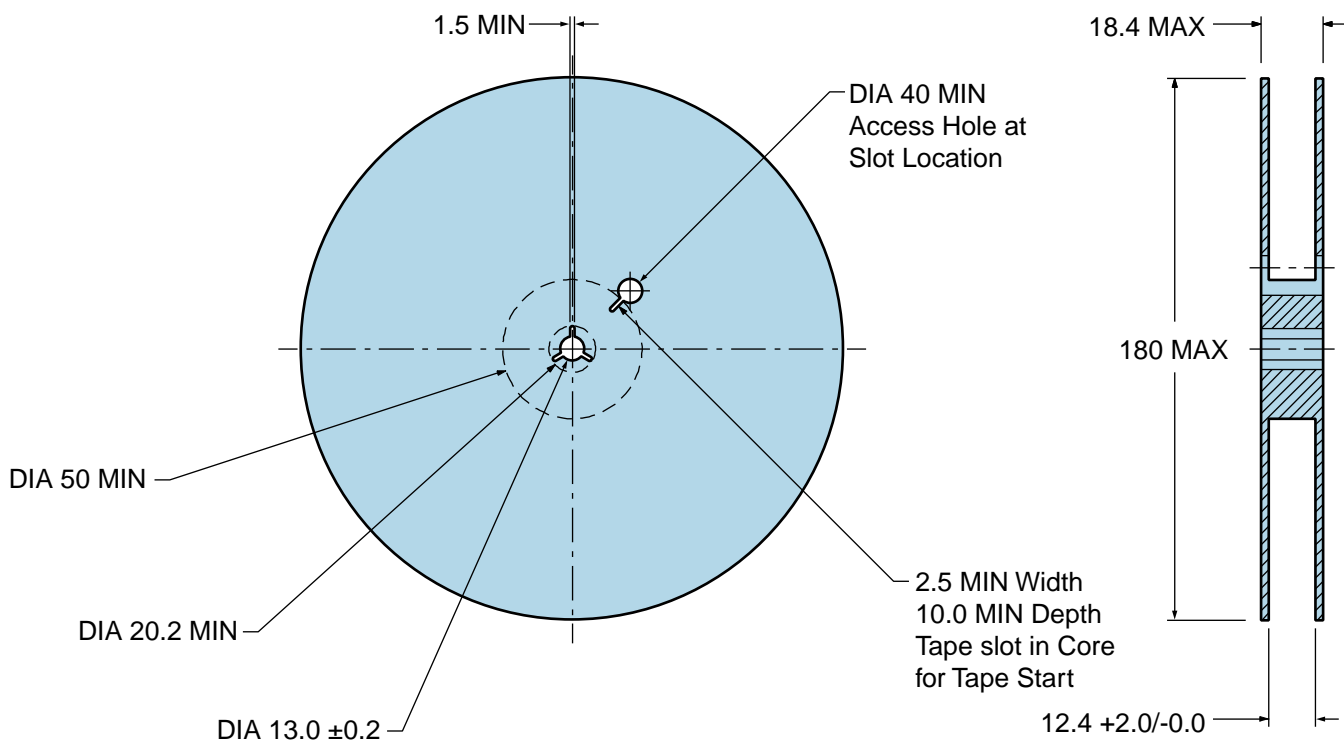
# EC3900TTS-50.000M TR

## Tape & Reel Dimensions

Quantity Per Reel: 1,000 units



\*Compliant to EIA 481A



## Recommended Solder Reflow Methods



### High Temperature Infrared/Convection

$T_s$ MAX to $T_L$ (Ramp-up Rate)	3°C/second Maximum
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#### Preheat

- Temperature Minimum ( $T_s$ MIN)	150°C
- Temperature Typical ( $T_s$ TYP)	175°C
- Temperature Maximum ( $T_s$ MAX)	200°C
- Time ( $t_s$ MIN)	60 - 180 Seconds

Ramp-up Rate ( $T_L$ to $T_p$ )	3°C/second Maximum
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#### Time Maintained Above:

- Temperature ( $T_L$ )	217°C
- Time ( $t_L$ )	60 - 150 Seconds

Peak Temperature ( $T_p$ )	260°C Maximum for 10 Seconds Maximum
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Target Peak Temperature ( $T_p$ Target)	250°C +0/-5°C
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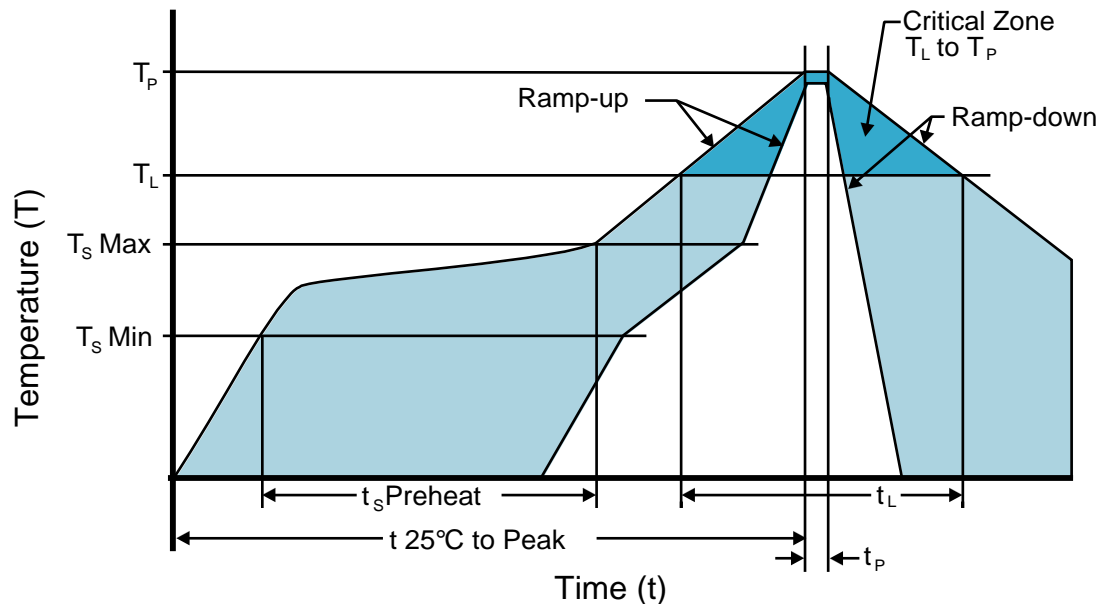
Time within 5°C of actual peak ( $t_p$ )	20 - 40 seconds
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Ramp-down Rate	6°C/second Maximum
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Time 25°C to Peak Temperature (t)	8 minutes Maximum
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Moisture Sensitivity Level	Level 1
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## Recommended Solder Reflow Methods



### Low Temperature Infrared/Convection 240°C

$T_s \text{ MAX to } T_L$  (Ramp-up Rate) 5°C/second Maximum

#### Preheat

- Temperature Minimum ( $T_s \text{ MIN}$ ) N/A
- Temperature Typical ( $T_s \text{ TYP}$ ) 150°C
- Temperature Maximum ( $T_s \text{ MAX}$ ) N/A
- Time ( $t_s \text{ MIN}$ ) 60 - 120 Seconds

Ramp-up Rate ( $T_L$  to  $T_p$ ) 5°C/second Maximum

#### Time Maintained Above:

- Temperature ( $T_L$ ) 150°C
- Time ( $t_L$ ) 200 Seconds Maximum

Peak Temperature ( $T_p$ ) 240°C Maximum

Target Peak Temperature ( $T_p \text{ Target}$ ) 240°C Maximum 1 Time / 230°C Maximum 2 Times

Time within 5°C of actual peak ( $t_p$ ) 10 seconds Maximum 2 Times / 80 seconds Maximum 1 Time

Ramp-down Rate 5°C/second Maximum

Time 25°C to Peak Temperature (t) N/A

Moisture Sensitivity Level Level 1

### Low Temperature Manual Soldering

185°C Maximum for 10 seconds Maximum, 2 times Maximum.

### High Temperature Manual Soldering

260°C Maximum for 5 seconds Maximum, 2 times Maximum.